



SGS-THOMSON
MICROELECTRONICS

SGS30MA050D1

N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR MODULE

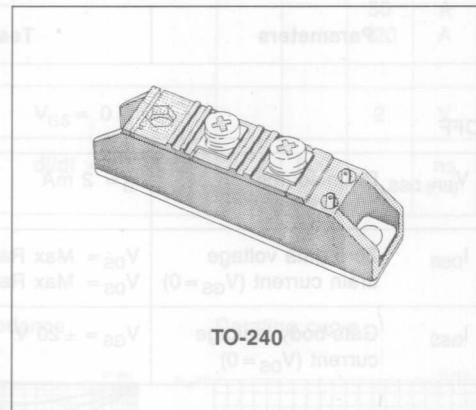
TYPE	V _{DSS}	R _{DS(on)}	I _D
SGS30MA050D1	500 V	0.20 Ω	30 A

- ISOLATED POWERMOS MODULE
- HIGH POWER
- FAST SWITCHING
- EASY DRIVE
- EASY TO PARALLEL

INDUSTRIAL APPLICATIONS:

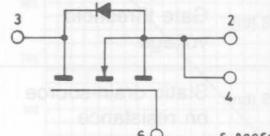
- SWITCHING MODE POWER SUPPLIES
- UNINTERRUPTIBLE POWER SUPPLIES

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and fast switching of this TRANSPACK module make it ideal for high power, high speed switching applications. Typical applications include DC motor control (variable frequency control) switching mode power supplies, uninterruptible power supplies, DC/DC convertors and high frequency welding equipment. The large RBSOA and absence of second breakdown in POWER MOS make this TRANSPACK module very rugged. This, together with the isolated package with its optimised thermal performance, make this module extremely effective in high power applications.



TO-240

INTERNAL SCHEMATIC DIAGRAM



S-8005/I

Parameter	Rating	Unit	Notes
V _{DS}	Drain-source voltage (V _{GS} =0)	V	500
V _{DGR}	Drain-gate voltage (R _{GS} =20 kΩ)	V	500
V _{GS}	Gate-source voltage	V	±20
I _D	Drain current (cont.) at T _c =25°C	A	30
I _D	Drain current (cont.) at T _c =100°C	A	19
I _{DM}	Drain current (pulsed)	A	120
P _{tot}	Total dissipation at T _c < 25°C	W	400
	Derating factor	W/C	3.2
T _{stg}	Storage temperature	°C	-65 to 150
T _j	Max. operating junction temperature	°C	150
V _{ISO}	Insulation withstand voltage (AC)	V	2500

THERMAL DATA

$R_{thj - case}$	Thermal resistance junction-case	max	0.31	°C/W
$R_{thc - h}$	Thermal resistance case-heatsink	max	0.20	°C/W

ELECTRICAL CHARACTERISTICS ($T_j = 25^\circ\text{C}$ unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
<i>Note:</i> All characteristics are guaranteed by test, except where noted by <i>Typ.</i> or <i>Min./Max.</i>					
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$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage $I_D = 2 \text{ mA}$ $V_{GS} = 0$	500			V
I_{DSS}	Zero gate voltage drain current ($V_{GS} = 0$) $V_{DS} = \text{Max Rating}$ $V_{DS} = \text{Max Rating} \times 0.8$ $T_j = 125^\circ\text{C}$	500 2			μA mA
I_{GSS}	Gate-body leakage current ($V_{DS} = 0$) $V_{GS} = \pm 20 \text{ V}$			± 400	nA
<i>Note:</i> All characteristics are guaranteed by test, except where noted by <i>Typ.</i> or <i>Min./Max.</i>					
$V_{GS(\text{th})}$	Gate threshold voltage $V_{DS} = V_{GS}$	$I_D = 2 \text{ mA}$	2		V
$R_{DS(\text{on})}$	Static drain-source on resistance $V_{GS} = 10 \text{ V}$	$I_D = 15 \text{ A}$		0.20	Ω

DYNAMIC

g_{fs}	Forward transconductance $V_{DS} = 25 \text{ V}$	$I_D = 15 \text{ A}$	15		mho
C_{iss} C_{oss} C_{rss}	Input capacitance Output capacitance Reverse transfer capacitance $V_{DS} = 25 \text{ V}$ $V_{GS} = 0$	$f = 1 \text{ MHz}$		9100 1200 850	pF pF pF

SWITCHING

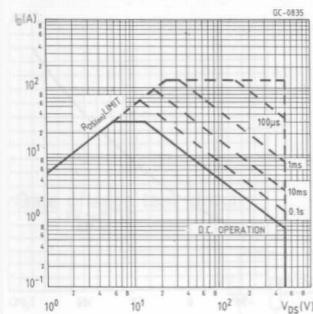
INDUCTIVE LOAD					
$t_d(\text{on})$	Turn-on time $V_{DD} = 250 \text{ V}$	$I_D = 15 \text{ A}$	120		ns
(di/dt) _{on}	Turn-on current slope $R_i = 50 \Omega$	$V_i = 10 \text{ V}$	100		A/ μs
$t_d(\text{off})$	Turn-off delay time		1.5		μs
t_f	Fall time		300		ns

ELECTRICAL CHARACTERISTICS (Continued)

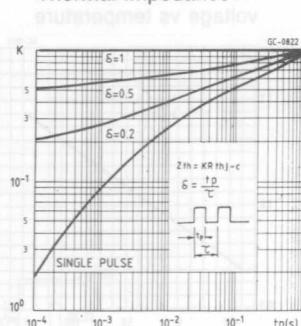
Parameters	Test Conditions		Min.	Typ.	Max.	Unit
SOURCE DRAIN DIODE						
I _{SD} I _{SDM}	Source-drain current Source-drain current (pulsed)				30 120	A A
V _{SD}	Forward on voltage	I _{SD} = 30 A	V _{GS} = 0		2	V
t _{rr}	Reverse recovery time	I _{SD} = 30 A	di/dt = 150A/μs	600		ns

* Pulsed: Pulse duration $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$

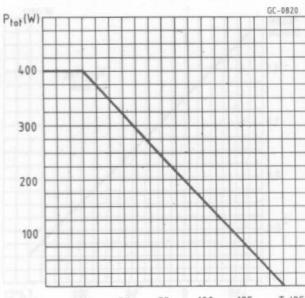
Safe operating areas



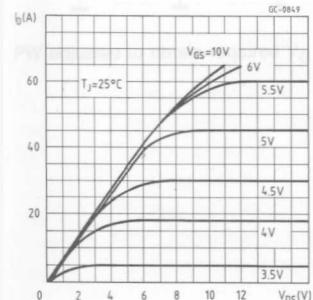
Thermal impedance



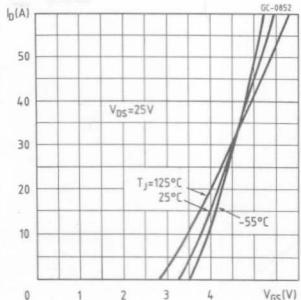
Derating curve



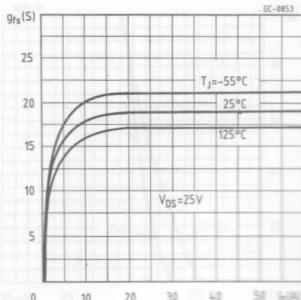
Output characteristics



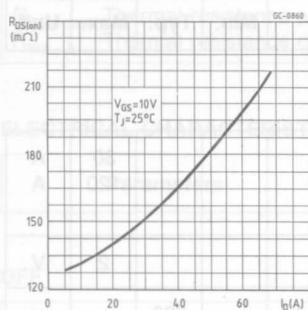
Transfer characteristics



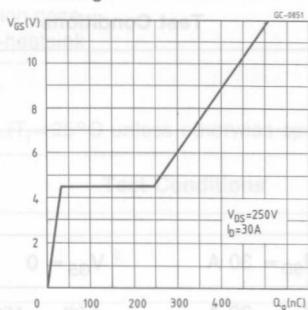
Transconductance



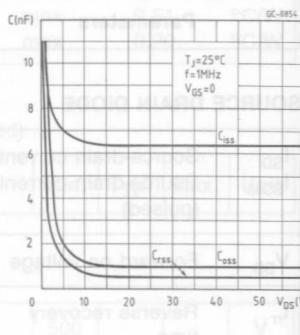
Static drain-source on resistance



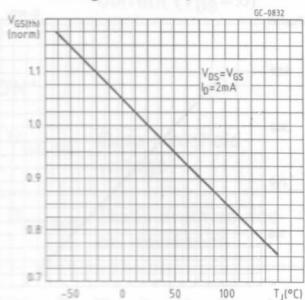
Gate charge vs gate-source voltage



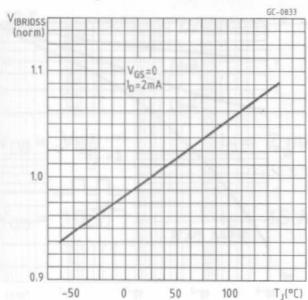
Capacitance variation



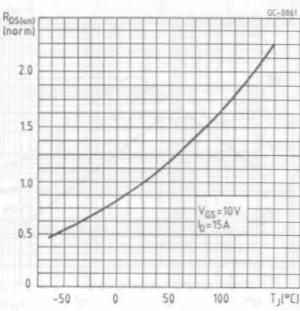
Normalized gate threshold voltage vs temperature



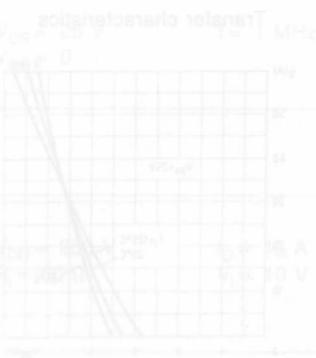
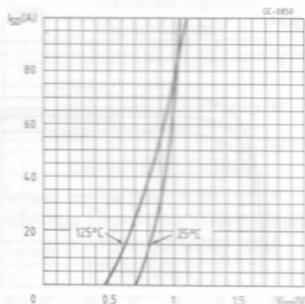
Normalized breakdown voltage vs temperature



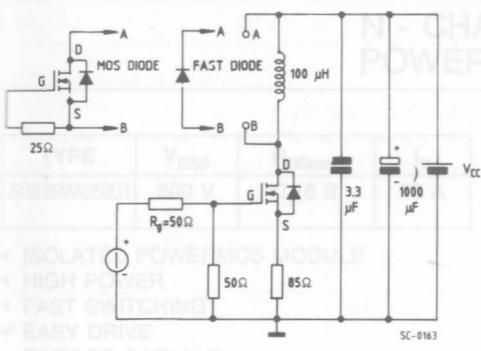
Normalized on resistance vs temperature



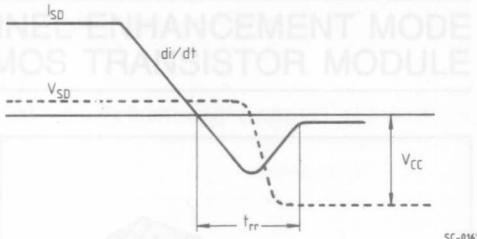
Source-drain diode forward characteristics



Test circuit for inductive load switching and diode reverse recovery times



Diode reverse recovery time waveform



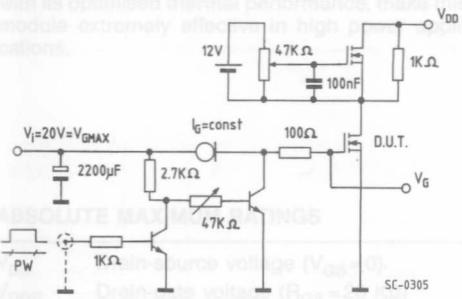
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PACK module very

Gate charge test circuit

For accurate measurement of the isolated package with respect to electrical performance, make the module extremely simple and high voltage options.



PW adjusted to obtain required V_G

Drain current (cont.) at $T_c = 25^\circ\text{C}$

Drain current (pulsed)

Total dissipation at $T_c < 25^\circ\text{C}$

Darating factor

Storage temperature

Max. operating junction temperature

Insulation withstand voltage (AC)

INTERNAL SCHEMATIC DIAGRAM



500	V
500	V
±20	A
35	A
22	A
140	A
400	W
8.2	V _G
65 to 150	°C
150	°C
2500	V